

# **RF Exposure Report**

**Report No.:** SA180131E02

FCC ID: HV4-HSNW001P

Test Model: HSN-W001P

Received Date: Jan. 16, 2018

Test Date: Jan. 16, 2018

Issued Date: Feb. 27, 2018

Applicant: Wacom Co., Ltd.

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Issued By: Bureau Veritas Consumer Products Services (H.K.) Ltd., Taoyuan Branch

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# **Release Control Record**

Issue No.	Description	Date Issued
SA180131E02	Original release.	Feb. 27, 2018



# 1 Certificate of Conformity

Product: HP Active Pen G2

Brand: hp

Test Model: HSN-W001P

Sample Status: ENGINEERING SAMPLE

Applicant: Wacom Co., Ltd.

Test Date: Jan. 16, 2018

Standards: FCC Part 2 (Section 2.1093)

KDB 447498 D01 General RF Exposure Guidance v06

IEEE C95.1-1992

The above equipment has been tested by **Bureau Veritas Consumer Products Services (H.K.) Ltd., Taoyuan Branch**, and found compliance with the requirement of the above standards. The test record, data evaluation & Equipment Under Test (EUT) configurations represented herein are true and accurate accounts of the measurements of the sample's EMC characteristics under the conditions specified in this report.

Prepared by : \_\_\_\_\_\_\_, Date: \_\_\_\_\_\_ Feb. 27, 2018

Mary Ko / Specialist

**Approved by :** , **Date:** Feb. 27, 2018

May Chen / Manager



#### 2 Evaluation Result

Following FCC KDB 447498 D01 "General SAR test exclusion guidance"

The corresponding SAR Exclusion Threshold condition, listed below:

1) The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)]  $\cdot [\sqrt{f(GHz)}] \le 3.0$  for 1-g SAR and  $\le 7.5$  for 10-g extremity SAR, where

- f(GHz) is the RF channel transmit frequency in GHz.
- Power and distance are rounded to the nearest mW and mm before calculation.
- ➤ The result is rounded to one decimal place for comparison The test exclusions are applicable only when the minimum test separation distance is ≤ 50 mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.</p>
- 2) At 100 MHz to 6 GHz and for test separation distances > 50 mm, the SAR test exclusion threshold is determined according to the following:
  - a) [Threshold at 50 mm in step 1) + (test separation distance 50mm)·( f(MHz)/150)] mW, at 100MHz to 1500 MHz
  - b) [Threshold at 50 mm in step 1) + (test separation distance 50 mm)·10] mW at > 1500 MHz and ≤ 6 GHz
- 3) At frequencies below 100 MHz, the following may be considered for SAR test exclusion.
  - a) The threshold at the corresponding test separation distance at 100 MHz in step 2) is multiplied by [1 + log(100/f(MHz))] for test separation distances > 50 mm and < 200 mm.
  - b) The threshold determined by the equation in a) for 50 mm and 100 MHz is multiplied by  $\frac{1}{2}$  for test separation distances  $\leq$  50 mm.
  - c) SAR measurement procedures are not established below 100 MHz. When SAR test exclusion cannot be applied, a KDB inquiry is required to determine SAR evaluation requirements for any test results to be acceptable.



# 3 SAR Test Exclusion Thresholds

**BT-LE Avg. Power Table** 

Channel	Frequency (MHz)	Peak Power		Avg. Power	
		(mW)	(dBm)	(mW)	(dBm)
0	2402	2.307	3.63	2.291	3.60
19	2440	2.123	3.27	2.109	3.24
39	2480	1.888	2.76	1.875	2.73

### For BT-LE SAR Test Exclusion Thresholds

Frequency (GHz)	Max Avg. Power (dBm)	Power Avg. Power Avg. P		Min. test separation distance (mm) SAR test exclusion calculation value (NOTE 1)		10-g SAR test exclusion thresholds	Result
2.402 ~ 2.480	3.6	1.86	1.535	5	0.476	7.5	Pass

NOTE: 1. The antenna type is chip antenna with 2.93dBi gain.

- 2. Calculate SAR test exclusion thresholds from condition "1" formulas.
- 3. \*Time Avg. Power= Avg. Power+Duty factor

**BT-LE Duty Cycle of Test Signal** 

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Duty Cycle	Tx on Tx total (ms) (ms)		Duty Factor (dB)				
, ,	0.42	0.627	-1.74				
Duty Factor =10 * log(Tx on / Tx total)							



# 4 Conclusion

Since Source-base time average power is below SAR test exclusion power thresholds, the SAR evaluation is not required.

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